Notice of References Cited Application/Control No. 10/738,910 Examiner John P. Sheehan Applicant(s)/Patent Under Reexamination DARDIK ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-4,906,877	03-1990	Ciaio, Frank A.	310/11
*	В	US-3,759,635	09-1973	Carter et al.	417/50
	С	US-			
	۵	US-			
	ш	US-			
	F	US-			
	G	US-			
	Ξ	US-			
	-	US-			
	J	US-			
	К	US-			
	٦	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	10-144521	05-1998	Japan	Nakamura et al.	
	0					
	Р					
	Q					
	R					
	S					
	T	•				

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	×	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.